

**P- Channel Enhancement Mode MOSFET**
**◆ DESCRIPTION**

The MT4435 MOSFET from MATRIX provide the designer with the best combination of fast switching, Buggerized device design, low on-resistance and cost-effectiveness.

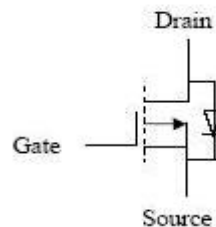
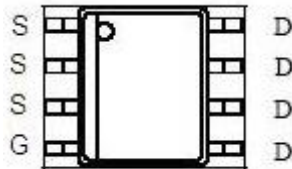
The SO-8 package is universally preferred for all commercial-industrial surface mount applications and suited for low voltage applications such as DC/DC converters.

**◆ FEATURES**

- -30V/-8A,  $R_{DS(ON)} = 20m\Omega @ V_{GS} = -10V$
- SO-8 package design
- Simple Drive Requirement
- Low On-resistance
- Fast Switching

**◆ APPLICATIONS**

- POWER Management in Note
- Portable Equipment
- Battery Powered System
- DC/DC Converter
- Load Switch

**◆ PIN CONFIGURATION**

**◆ ABSOLUTE MAXIMUM RATINGS**

( $T_A=25^\circ C$  Unless Otherwise Noted)

Parameter	Symbol	Maximum	Unit
Drain-Source Voltage	$V_{DS}$	-30	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>3</sup>	$I_D$	$T_A=25^\circ C$	-8
		$T_A=70^\circ C$	-6
Pulsed Drain Current <sup>1,2</sup>	$I_{DM}$	-50	A
Total Power Dissipation	$P_D$	2.5	W
Linear Derating Factor		0.02	W/ $^\circ C$
Storage Temperature Range	$T_{STG}$	-55 to 150	$^\circ C$
Operating Junction Temperature Range	$T_J$	- 55 to 150	$^\circ C$

**P- Channel Enhancement Mode MOSFET**
**◆ THERMAL RESISTANCE RATINGS**

Thermal Resistance	Symbol	Maximum	Unit
Thermal Resistance Junction-ambient	$R_{thj-a}$	50	$^{\circ}\text{C}/\text{W}$

**◆ ELECTRICAL CHARACTERISTICS**

 ( $T_A=25^{\circ}\text{C}$  Unless Otherwise Noted)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
<b>Static Parameters</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	$V_{GS} = 0\text{V}, I_D = -250\mu\text{A}$	-30	-	-	V
Breakdown Voltage Temperature Coefficient	$\Delta BV_{DSS}/\Delta T_j$	Reference to $25^{\circ}\text{C}, I_D = -1\text{mA}$	-	-0.04	-	$\text{V}/^{\circ}\text{C}$
Static Drain-Source On-Resistance	$R_{DS(ON)}$	$V_{GS} = -10\text{V}, I_D = -8\text{A}$	-	15	20	m $\Omega$
		$V_{GS} = -4.5\text{V}, I_D = -5\text{A}$	-	26	32	
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	-1	-	-3	V
Forward Transconductance	$g_{fs}$	$V_{DS} = -15\text{V}, I_D = -8\text{A}$	-	20	-	S
Drain-Source Leakage Current	$I_{DSS}$	$T_J=25^{\circ}\text{C}$ $V_{DS} = -30\text{V}, V_{GS} = 0\text{V}$	-	-	-1	uA
		$T_J=70^{\circ}\text{C}$ $V_{DS} = -24\text{V}, V_{GS} = 0\text{V}$	-	-	-25	
Gate-Source Leakage	$I_{GSS}$	$V_{GS} = \pm 20\text{V}$	-	-	$\pm 100$	nA
<b>Dynamic Parameters</b>						
Total Gate Charge <sup>2</sup>	$Q_g$	$I_D = -4.6\text{A}, V_{DS} = -15\text{V}, V_{GS} = -10\text{V}$	-	36	-	nc
Gate-Source Charge	$Q_{gs}$		-	5.5	-	
Gate-Drain("Miller")Charge	$Q_{gd}$		-	3.5	-	
Turn-on Delay Time <sup>2</sup>	$t_{d(on)}$	$V_{DS} = -15\text{V}, I_D = -1\text{A}, R_G = 6\Omega, V_{GS} = -10\text{V}, R_D = 15\Omega$	-	12	-	ns
Rise Time	$t_r$		-	8	-	
Turn-off Delay Time	$T_{d(off)}$		-	75	-	
Fall time	$T_f$		-	40	-	
Input Capacitance	$C_{iss}$	$V_{GS} = 0\text{V}, V_{DS} = -15\text{V}, f = 1.0\text{MHz}$	-	1530	-	pF
Output Capacitance	$C_{oss}$		-	900	-	
Reverse Transfer Capacitance	$C_{rss}$		-	280	-	
Gate Resistance	$R_g$	$F = 1.0\text{MHz}$	-	6	9	$\Omega$

**P- Channel Enhancement Mode MOSFET**
**◆ Source-Drain Diode**

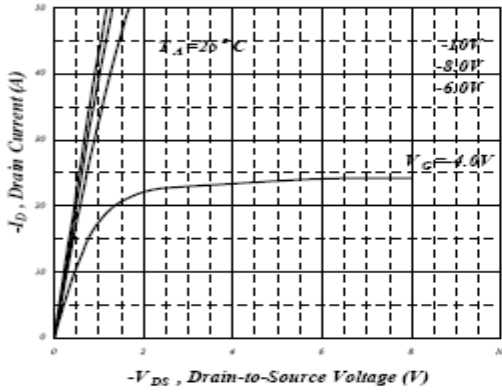
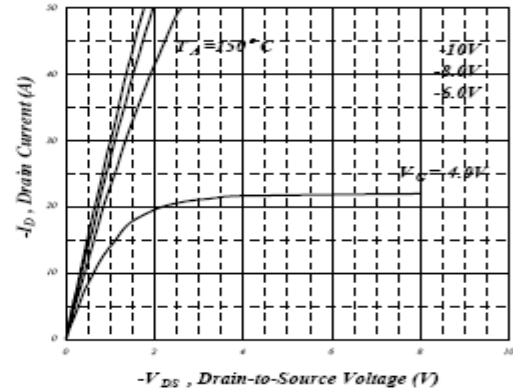
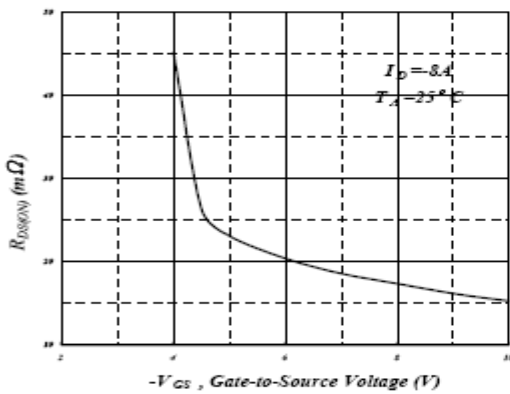
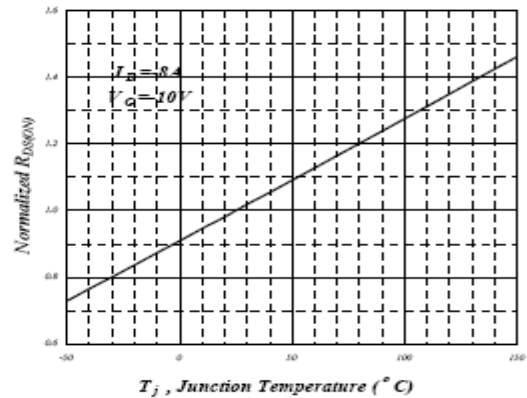
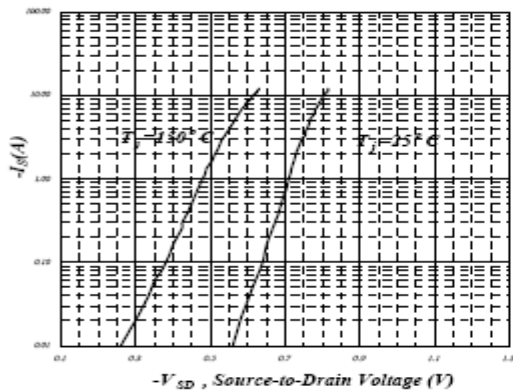
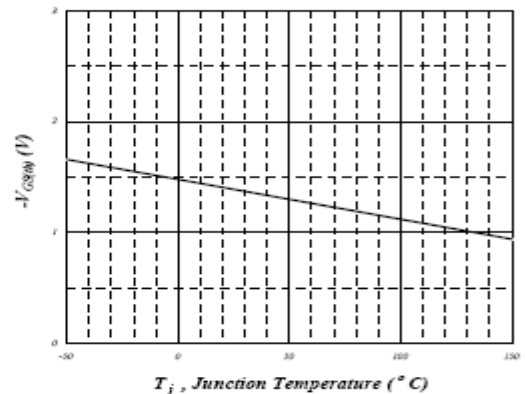
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Forward On Voltage <sup>2</sup>	$V_{SD}$	$I_S = -2.1A, V_{GS} = 0V$	-	-	-1.2	V
Reverse Recovery Time <sup>2</sup>	$t_{rr}$	$I_S = -5A, V_{GS} = 0V,$	-	55	-	ns
Reverse Recovery Charge	$Q_{rr}$	$di/dt = 100A/us$	-	83	-	nc

**Notes:**

1. Pulse width limited by Max. junction temperature.
2. Pulse width  $\leq 300us$ , duty cycle  $\leq 2\%$
3. Surface mounted on 1 in<sup>2</sup> copper pad of FR4 board,  $t \leq 10sec$ ; 125°CW when mounted on Min.copper pad.

**P- Channel Enhancement Mode MOSFET**
**◆ TYPICAL CHARACTERISTICS**

(25°C Unless Noted)


**Fig 1. Typical Output Characteristics**

**Fig 2. Typical Output Characteristics**

**Fig 3. On-Resistance v.s. Gate Voltage**

**Fig 4. Normalized On-Resistance v.s. Junction Temperature**

**Fig 5. Forward Characteristic of Reverse Diode**

**Fig 6. Gate Threshold Voltage v.s. Junction Temperature**

P- Channel Enhancement Mode MOSFET

◆ TYPICAL CHARACTERISTICS

(25°C Unless Noted)

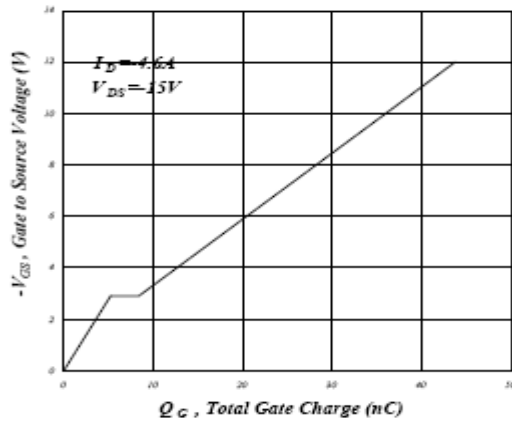


Fig 7. Gate Charge Characteristics

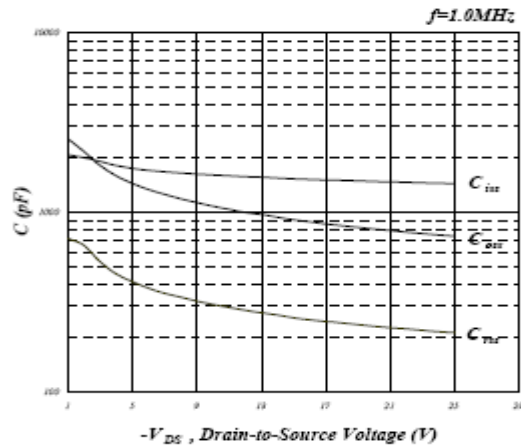


Fig 8. Typical Capacitance Characteristics

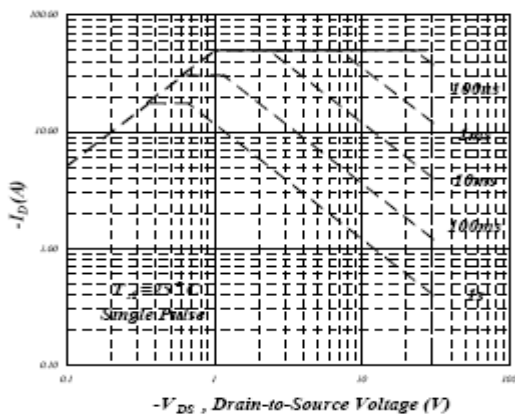


Fig 9. Maximum Safe Operating Area

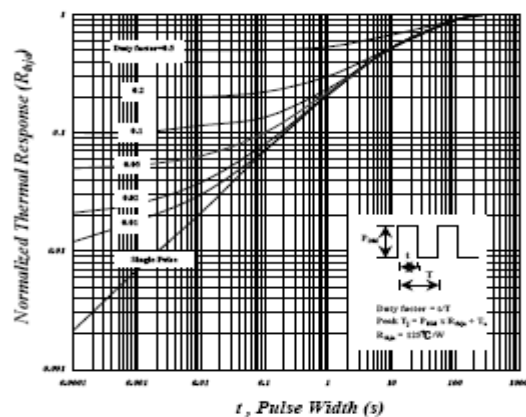


Fig 10. Effective Transient Thermal Impedance

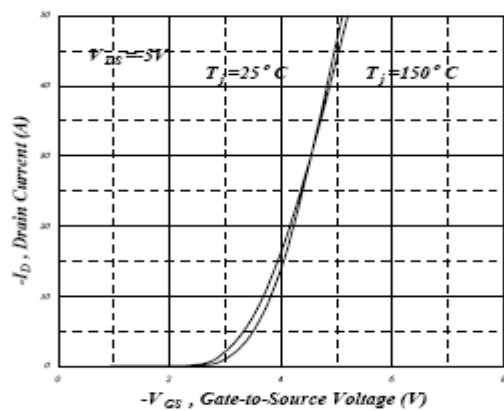


Fig 11. Transfer Characteristics

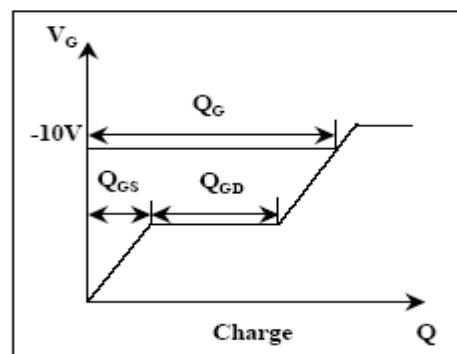


Fig 12. Gate Charge Circuit

**P- Channel Enhancement Mode MOSFET**
**◆ PHYSICAL DIMENSIONS:**
**8-Pin Plastic S.O.I.C. (M)**
